GND 7

SDZS014A - APRIL 1990 - REVISED JANUARY 1999

- 10KH Compatible
- TTL Clock and ECL Control Inputs
- Noninverting Outputs
- Flow-Through Architecture Optimizes PCB Layout
- Center Pin V_{CC}, V_{EE}, and GND Configurations Minimize High-Speed Switching Noise
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015
- Package Options Include Plastic Small-Outline (DW) Package and Standard Plastic (NT) DIPs

description

This octal TTL-to-ECL translator is designed to provide efficient translation between a TTL signal environment and a 10KH ECL signal environment. This device is designed specifically to improve the performance and density of TTL-to-ECL CPU/bus-oriented functions such as memory address drivers, clock drivers, and bus-oriented receivers and transmitters.

DW OR NT PACKAGE

GND 8 17 CLK(TTL)
5Q 9 16 50
6Q 10 15 6D
7Q 11 14 7D
8Q 12 13 8D

18 \ V_{EE}

The eight flip-flops of the '5578 are edge-triggered D-type flip-flops. On the positive transition of the clock, the Q outputs are set to the logic levels that were set up at the D inputs.

The output-control input \overline{OE} does not affect the internal operations of the flip-flops. Old data can be retained or new data can be entered while the outputs are off.

The SN10KHT5578 is characterized for operation from 0°C to 75°C.

FUNCTION TABLE

	OUTPUT		
ŌĒ	CLK	D	(ECL) Q
L	↑	L	L
L	↑	Н	Н
L	L	Х	Q ₀
Н	Х	Х	L

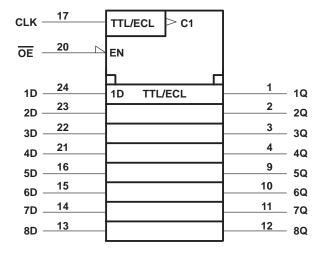


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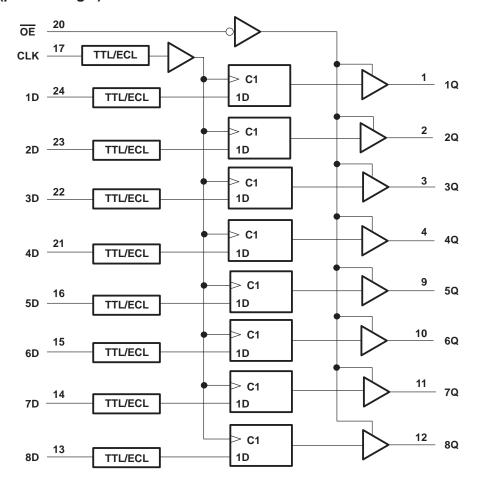
SDZS014A - APRIL 1990 - REVISED JANUARY 1999

logic symbol†



[†]This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)





SN10KHT5578 OCTAL TTL-TO-ECL TRANSLATOR WITH D-TYPE EDGE-TRIGGERED FLIP-FLOPS AND OUTPUT ENABLE

SDZS014A – APRIL 1990 – REVISED JANUARY 1999

absolute maximum ratings over operating ambient temperature range (unless otherwise noted) [†]
Supply voltage range, V _{CC} –0.5 V to 7 V
Supply voltage range, VEE8 V to 0 V
Input voltage range (TTL) (see Note 1)
Input voltage range (ECL) V _{EE} to 0 V
Input current range (TTL)
Current out of any output 50 mA
Package thermal impedance, θ _{JA} (see Note 2): DW package
NT package 67°C/W
Storage temperature range—65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The TTL input voltage ratings may be exceeded provided the input current ratings are observed.

recommended operating conditions

			MIN	NOM	MAX	UNIT
Vcc	TTL supply voltage		4.5	5	5.5	V
V _{EE} ECL supply voltage		-4.94	-5.2	-5.46	V	
VIH	VIH TTL high-level input voltage		2			V
		0°C	-1170		-840	mV
V _{IH} ECL hi	ECL high-level input voltage [‡]	25°C	-1130		-810	mV
		75°C	-1070		-735	mV
V _{IL}	TTL low-level input voltage				0.8	V
		0°C -1950		-1480	mV	
VIL	ECL low-level input voltage [‡]	25°C	-1950		-1480	mV
		75°C	-1950		-1450	mV
I _{IK} TTL input clamp current				-18	mA	
TA Operating ambient temperature (see Note 3)		0		75	°C	

[‡] The algebraic convention, in which the least positive (most negative) value is designated minimum, is used in this data sheet for logic levels only. NOTE 3: Each 10KH-series circuit has been designed to meet the dc specifications shown in the electrical characteristics table after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board, and transverse airflow greater than 500 linear ft/min is maintained.



^{2.} The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

SN10KHT5578 OCTAL TTL-TO-ECL TRANSLATOR WITH D-TYPE EDGE-TRIGGERED FLIP-FLOPS AND OUTPUT ENABLE SDZS014A – APRIL 1990 – REVISED JANUARY 1999

electrical characteristics over recommended operating ambient temperature range (unless otherwise noted)

1	PARAMETER		TEST CONDITION	NS		MIN	TYP [†]	MAX	UNIT
VIK	CLK and D inputs	V _{CC} = 4.5 V,	V _{EE} = -4.94 V,	I _I = –18 mA				-1.2	V
lį	CLK and D inputs	V _{CC} = 5.5 V,	$V_{EE} = -5.46 \text{ V},$	V _I = 7 V				0.1	mA
	CLK and D inputs	V _{CC} = 5.5 V,	VEE = −5.46 V,	V _I = 2.7 V				20	
1		$V_{CC} = 5.5 \text{ V},$	$V_{EE} = -5.46 \text{ V},$	$V_{I} = -840 \text{ mV}$	0°C			350	
ΊΗ	OE input	$V_{CC} = 5.5 \text{ V},$	$V_{EE} = -5.46 \text{ V},$	$V_{I} = -810 \text{ mV}$	25°C			350	μΑ
		$V_{CC} = 5.5 \text{ V},$	$V_{EE} = -5.46 \text{ V},$	$V_{I} = -735 \text{ mV}$	75°C			350	
	CLK and D inputs	$V_{CC} = 5.5 \text{ V},$	$V_{EE} = -5.46 \text{ V},$	V _I = 0.5 V				-0.5	mA
ļ					0°C	0.5			
¹ı∟	OE input	$V_{CC} = 5.5 \text{ V},$	$V_{EE} = -5.46 \text{ V},$	$V_{I} = -1950 \text{ mV}$	25°C	0.5			μΑ
					75°C	0.5			
					0°C	-1020		-840	
VOH [‡]		$V_{CC} = 4.5 \text{ V},$	$V_{EE} = -5.2 V \pm 5\%$,	See Note 4	25°C	-980		-810	mV
					75°C	-920		-735	
					0°C	-1950		-1630	
V _{OL} ‡		$V_{CC} = 4.5 \text{ V},$	$V_{EE} = -5.2 V \pm 5\%$,	See Note 4	25°C	-1950		-1630	mV
					75°C	-1950		-1600	
ICCH		$V_{CC} = 5.5 \text{ V},$	$V_{EE} = -5.46 \text{ V}$				17.5	25	mA
ICCL	<u> </u>	$V_{CC} = 5.5 \text{ V},$	$V_{EE} = -5.46 \text{ V}$	·			15	22	mA
IEE		$V_{CC} = 5.5 \text{ V},$	VEE = −5.46 V				-104	-149	mA
Ci		$V_{CC} = 5 V$,	$V_{EE} = -5.2 \text{ V},$	f = 10 MHz			4		pF

[†] All typical values are at $V_{CC} = 5 \text{ V}$, $V_{EE} = -5.2 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

timing requirements over recommended operating conditions

			MIN	MAX	UNIT
fclock	Clock frequency			180	MHz
	Pulse duration, CLK	High	4		no
t _W		Low	4		ns
t _{SU} Se	Cotum time data hatara CLIVA	High	1.5		
	Setup time, data before CLK↑	Low	2.5		ns
. .	Hold time, data after CLK↑	High	1		ns
th		Low	1		115

switching characteristics over recommended ranges of supply voltage and operating ambient temperature (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN	TYP	MAX	UNIT
f _{max}			180			MHz
^t PLH	CLK	0	0.8	2.2	4	no
t _{PHL}		Q	0.8	2.1	3.8	ns
^t PLH	OE	0	0.5	1.4	3.2	no
t _{PHL}		Q	0.5	1.7	3.3	ns
t _r		Y		1.5		ns
t _f		Υ		1.5		ns

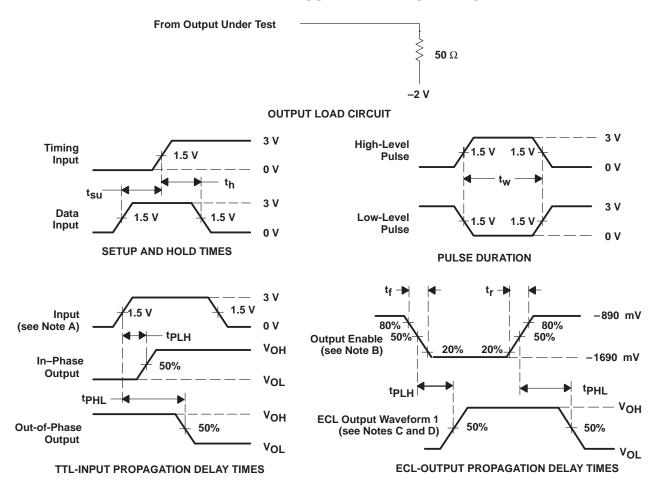
[†] All typical values are at $V_{CC} = 5 \text{ V}$, $V_{EE} = -5.2 \text{ V}$, $T_A = 25^{\circ}\text{C}$.



[‡] The algebraic convention, in which the least positive (most negative) value is designated minimum, is used in this data sheet for logic levels only. NOTE 4: Outputs are terminated through a $50-\Omega$ resistor to -2 V.

SDZS014A – APRIL 1990 – REVISED JANUARY 1999

PARAMETER MEASUREMENT INFORMATION



NOTES: A. For TTL inputs, input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_O = 50 Ω , $t_f = 2.5$ ns, $t_f = 2.5$ ns.

- B. For ECL inputs, input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_O = 50 Ω , $t_f = 1.5$ ns, $t_f = 1.5$ ns.
- C. Waveform 1 is for an output with internal conditions such that the output is high except when disabled by $\overline{\text{OE}}$.
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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